Search Notes							

Application/Control No.	Applicant(s)/Patent under Reexamination	_
10/734,226	LEE ET AL.	
Examiner	Art Unit	
Eric B. Chen	1765	

	SEARCHED		
Class	Subclass	Date	Examiner

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
Inventor search (UPDATED)	11/28/2005	EC
EAST (all databases) (UPDATED) - see search history printout	11/28/2005	EC
438/3,706,710,719,720,911 (text search only) (UPDATED)	11/28/2005	EC